


APPLICATION DATA SHEET

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Title of Invention	[METHOD FOR DETECTING DEFECT OF SEMICONDUCTOR DEVICE]		
Application Type : regular, utility Attorney Docket Number : 11535-US-PA			
Correspondence address: Customer Number: 31561 			
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Inventors Information: <u>Inventor 1:</u> Applicant Authority Type: Inventor Citizenship: TW Name prefix: Mr. Given Name: HOUNG-JIE Family Name: CHANG Residence: City of Residence: TAICHUNG COUNTY Country of Residence: TW Address-1 of Mailing Address: NO. 13, RENHE RD., HOULI TOWNSHIP Address-2 of Mailing Address: City of Mailing Address: TAICHUNG COUNTY State of Mailing Address: Postal Code of Mailing Address: Country of Mailing Address: TW Phone: Fax: E-mail: <u>Inventor 2:</u> Applicant Authority Type: Inventor			

Citizenship:	TW
Name prefix:	Mr.
Given Name:	SHENG-JU
Family Name:	CHANG
Residence:	
City of Residence:	HSINCHU CITY
Country of Residence:	TW
Address-1 of Mailing Address:	NO. 116, LANE 1200, MINGHU RD.
Address-2 of Mailing Address:	
City of Mailing Address:	HSINCHU CITY
State of Mailing Address:	
Postal Code of Mailing Address:	
Country of Mailing Address:	TW
Phone:	
Fax:	
E-mail:	

Attorney Information:

practitioner(s) at Customer Number:

31561



as our attorney(s) or agent(s) to prosecute the application identified above, and to transact all business in the United States Patent and Trademark Office connected therewith.